TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π–MOSIII)

## 2SK2611

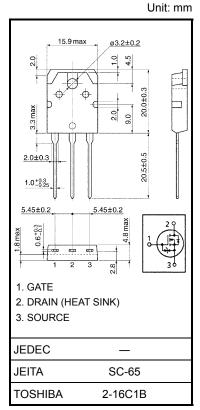
# DC-DC Converter, Relay Drive and Motor Drive Applications

• Low drain–source ON resistance :  $RDS (ON) = 1.1 \Omega (typ.)$ • High forward transfer admittance :  $|Y_{fs}| = 7.0 S (typ.)$ • Low leakage current :  $IDSS = 100 \mu A (max) (VDS = 720 V)$ 

• Low leakage current  $: I_{DSS} = 100 \,\mu\text{A} \,(\text{max}) \,(V_{DS} = 720 \,\text{V})$ • Enhancement-mode  $: V_{th} = 2.0 \sim 4.0 \,\text{V} \,(V_{DS} = 10 \,\text{V}, \,I_D = 1 \,\text{mA})$ 

#### Absolute Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	900	V	
Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)		$V_{DGR}$	900	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	I <sub>D</sub>	9	Α	
	Pulse (Note 1)	I <sub>DP</sub>	27	Α	
Drain power dissipation	n (Tc = 25°C)	$P_{D}$	150	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	663	mJ	
Avalanche current		I <sub>AR</sub>	9	А	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	15	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	Rth (ch-c)	0.833	°C / W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	50	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:  $V_{DD}$  = 90 V,  $T_{ch}$  = 25°C (initial), L = 15 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 9 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device.

Please handle with caution.



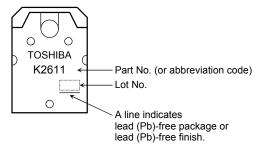
## **Electrical Characteristics (Ta = 25°C)**

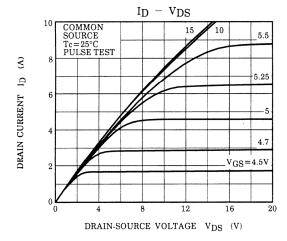
Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ
Gate-source bro	eakdown voltage	V (BR) GSS	I <sub>G</sub> = ±10 μA, V <sub>DS</sub> = 0 V	±30	_	_	V
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 720 V, V <sub>GS</sub> = 0 V	_	_	100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	900	_	_	V
Gate threshold	voltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4 A	_	1.1	1.4	Ω
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 4 A	3.0	7.0	_	S
Input capacitano	ce	C <sub>iss</sub>		_	2040	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	45	_	pF
Output capacitance		C <sub>oss</sub>		_	190	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $V_{OV}$ $V_{OU}$ $V_{OU}$ $V_{OU}$ $V_{OU}$ $V_{OU}$ $V_{OU}$ $V_{OU}$	_	25	_	
	Turn-on time	t <sub>on</sub>		_	60	_	no
	Fall time	t <sub>f</sub>		_	20	_	- ns
	Turn-off time	t <sub>off</sub>	Duty $\leq 1\%$ , $t_{\mathbf{W}} = 10 \mu s$	_	95	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	58	_	
Gate-source charge		Q <sub>gs</sub>	V <sub>DD</sub> ≈ 400 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 9 A		32	_	nC
Gate-drain ("miller") Charge		Q <sub>gd</sub>		_	26	_	

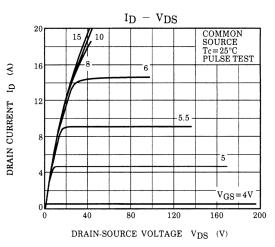
### Source-Drain Ratings and Characteristics (Ta = 25°C)

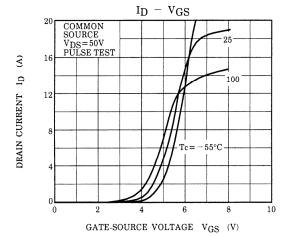
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	-	_	_	9	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	-	_	_	27	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 9 A, V <sub>GS</sub> = 0 V	_	_	-1.9	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 9 A, V <sub>GS</sub> = 0 V, dI <sub>DR</sub> / dt = 100 A / μs	_	1.6	_	μs
Reverse recovery charge	Qrr			20	_	μC

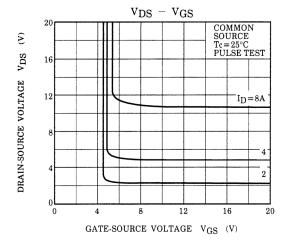
### Marking

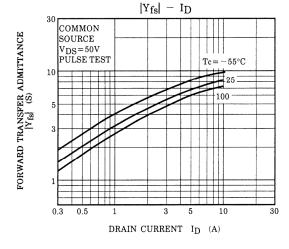


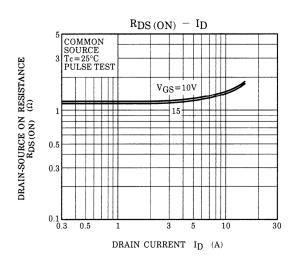




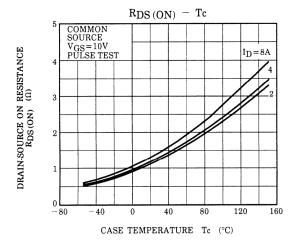


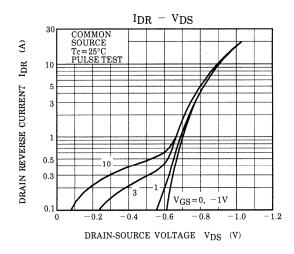


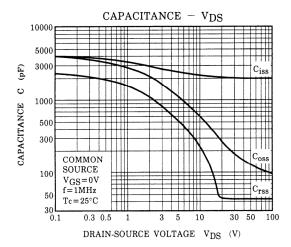


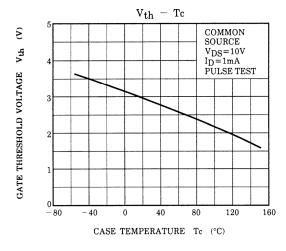


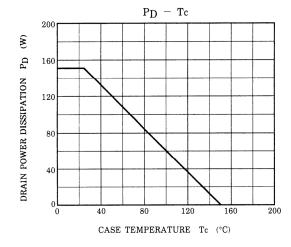
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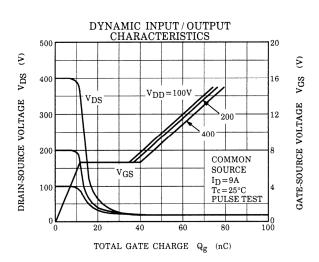




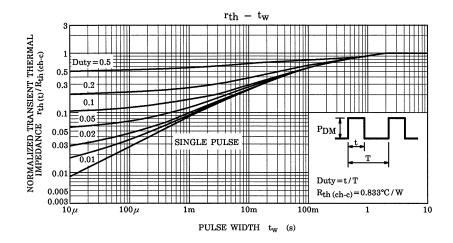


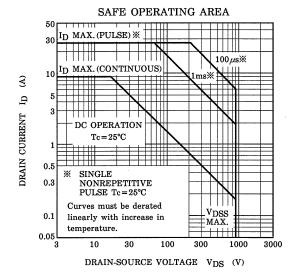


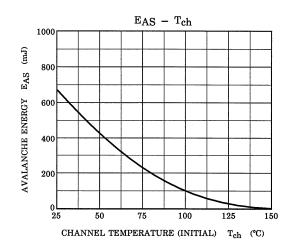


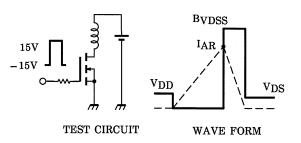


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$$R_G = 25 \Omega$$
  
 $V_{DD} = 90 \text{ V}, L = 15 \text{ mH}$   $E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}}\right)$ 

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